Search Notes



SPIE

IEEE Xplore

Application/Control No.

10814761

WILSON, ANDREW D.

Reexamination

Applicant(s)/Patent Under

Examiner

Hung, Yubin

Art Unit

2624

SEARCHED

Class	Subclass	Date	Examiner
382	103,106,154,171-173,180	9/25/07	YH
356	4.07	9/25/07	YH

SEARCH NOTES			
Search Notes	Date	Examiner	
EAST text search (USPGPUB, USPAT, EPO, JPO, DERWENT, IBM-TDB)	9/25/07	YH	
ACM	9/17/07	YH	

9/17/07

9/17/07

ΥH

ΥH

INTERFERENCE SEARCH						
Class	Subclass	Date	Examiner			
382	103, 106, 171-173, 180	9/25/07	YH			
356	4.07	9/25/07	YH			

U.S. Patent and Trademark Office Part of Paper No.: 20070925